Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/580,047	MURATORE ET AL.	
Examiner	Art Unit	
SVED ZAIDI	2616	

	SEARCHED				
Class	Subclass	Date	Examiner		
455	417	6/6/2008	SZ		
455	418	6/6/2008	SZ		
455	414.1	6/6/2008	SZ		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	7	PT = T			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	6/6/2008	SZ		
Inventor : MURATORE ET AL.	6/6/2008	SZ		
IEEE Xplore Database(http://ieeexplore.ieee.org/Xplore/DynWel.jsp)	6/6/2008	SZ		
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